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## Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I <sup>2</sup> C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I <sup>2</sup> S, POR, PWM, WDT
Number of I/O	18
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16К х 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 13x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	PG-VQFN-24-19
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1302q024x0032abxuma1

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# 2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

## 2.1 Logic Symbols



## Figure 2 XMC1300 Logic Symbol for TSSOP-38, TSSOP-28 and TSSOP-16



## 2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

#### Table 5 Package Pin Mapping Description

Function	Package A	Package B	 Pad Type
Px.y	Ν	Ν	Pad Class

The table is sorted by the "Function" column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The "Pad Type" indicates the employed pad type:

- STD\_INOUT(standard bi-directional pads)
- STD\_INOUT/AN (standard bi-directional pads with analog input)
- High Current (high current bi-directional pads)
- STD\_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameters.

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.0	23	17	13	15	7	STD_IN OUT	
P0.1	24	18	-	-	-	STD_IN OUT	
P0.2	25	19	-	-	-	STD_IN OUT	
P0.3	26	20	-	-	-	STD_IN OUT	
P0.4	27	21	14	-	-	STD_IN OUT	
P0.5	28	22	15	16	8	STD_IN OUT	
P0.6	29	23	16	17	9	STD_IN OUT	

#### Table 6 Package Pin Mapping



Table 0 Fackage Fill Mapping (cont d)										
Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes			
P2.1	2	36	26	2	-	STD_IN OUT/AN				
P2.2	3	37	27	3	-	STD_IN/ AN				
P2.3	4	38	-	-	-	STD_IN/ AN				
P2.4	5	1	-	-	-	STD_IN/ AN				
P2.5	6	2	28	-	-	STD_IN/ AN				
P2.6	7	3	1	4	16	STD_IN/ AN				
P2.7	8	4	2	5	1	STD_IN/ AN				
P2.8	9	5	3	5	1	STD_IN/ AN				
P2.9	10	6	4	6	2	STD_IN/ AN				
P2.10	11	7	5	7	3	STD_IN OUT/AN				
P2.11	12	8	6	8	4	STD_IN OUT/AN				
VSS	13	9	7	9	5	Power	Supply GND, ADC reference GND			
VDD	14	10	8	10	6	Power	Supply VDD, ADC reference voltage/ ORC reference voltage			
VDDP	15	10	8	10	6	Power	When VDD is supplied, VDDP has to be supplied with the same voltage.			

## Table 6 Package Pin Mapping (cont'd)





#### Figure 9 Simplified Port Structure

Pn.y is the port pin name, defining the control and data bits/registers associated with it. As GPIO, the port is under software control. Its input value is read via Pn\_IN.y, Pn\_OUT defines the output value.

Up to seven alternate output functions (ALT1/2/3/4/5/6/7) can be mapped to a single port pin, selected by Pn\_IOCR.PC. The output value is directly driven by the respective module, with the pin characteristics controlled by the port registers (within the limits of the connected pad).

The port pin input can be connected to multiple peripherals. Most peripherals have an input multiplexer to select between different possible input sources.

The input path is also active while the pin is configured as output. This allows to feedback an output to on-chip resources without wasting an additional external pin.

Please refer to the **Port I/O Functions** table for the complete Port I/O function mapping.



# 3 Electrical Parameters

This section provides the electrical parameters which are implementation-specific for the XMC1300.

## 3.1 General Parameters

## 3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1300 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

• CC

Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1300 and must be regarded for a system design.

SR

Such parameters indicate **S**ystem Requirements, which must be provided by the application system in which the XMC1300 is designed in.



## 3.1.2 Absolute Maximum Ratings

Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Parameter	Symbol			Va	lues	Unit	Note /	
			Min	Тур.	Max.		Test Cond ition	
Junction temperature	$T_{J}$	SR	-40	-	115	°C	-	
Storage temperature	$T_{\rm ST}$	SR	-40	-	125	°C	-	
Voltage on power supply pin with respect to $V_{\rm SSP}$	$V_{DDP}$	SR	-0.3	-	6	V	-	
Voltage on digital pins with respect to $V_{\rm SSP}{}^{1)}$	$V_{\sf IN}$	SR	-0.5	-	$V_{\text{DDP}}$ + 0.5 or max. 6	V	whichever is lower	
Voltage on P2 pins with respect to $V_{\rm SSP}^{2)}$	$V_{INP2}$	SR	-0.3	-	V <sub>DDP</sub> + 0.3	V	-	
Voltage on analog input pins with respect to $V_{\rm SSP}$	$V_{AIN}$ $V_{AREF}$	SR	-0.5	-	$V_{\text{DDP}}$ + 0.5 or max. 6	V	whichever is lower	
Input current on any pin during overload condition	I <sub>IN</sub>	SR	-10	-	10	mA	-	
Absolute maximum sum of all input currents during overload condition	ΣI <sub>IN</sub>	SR	-50	-	+50	mA	_	

Table 11	Absolute	Maximum	Rating	<b>Parameters</b>
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1) Excluding port pins P2.[1,2,6,7,8,9,11].

2) Applicable to port pins P2.[1,2,6,7,8,9,11].





#### Figure 10 Input Overload Current via ESD structures

 Table 13 and Table 14 list input voltages that can be reached under overload conditions.

 Note that the absolute maximum input voltages as defined in the Absolute Maximum Ratings must not be exceeded during overload.

#### Table 13 PN-Junction Characterisitics for positive Overload

Pad Type	<i>I</i> <sub>ov</sub> = 5 mA
Standard, High-current, AN/DIG_IN	$\begin{split} V_{\rm IN} &= V_{\rm DDP} + 0.5 \ V \\ V_{\rm AIN} &= V_{\rm DDP} + 0.5 \ V \\ V_{\rm AREF} &= V_{\rm DDP} + 0.5 \ V \end{split}$
P2.[1,2,6:9,11]	$V_{\rm INP2}$ = $V_{\rm DDP}$ + 0.3 V

#### Table 14 PN-Junction Characterisitics for negative Overload

Pad Type	<i>I</i> <sub>ov</sub> = 5 mA
Standard, High-current, AN/DIG_IN	$\begin{split} V_{\rm IN} &= V_{\rm SS} - 0.5 \ {\rm V} \\ V_{\rm AIN} &= V_{\rm SS} - 0.5 \ {\rm V} \\ V_{\rm AREF} &= V_{\rm SS} - 0.5 \ {\rm V} \end{split}$
P2.[1,2,6:9,11]	$V_{\rm INP2}$ = $V_{\rm SS}$ - 0.3 V



## 3.1.4 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC1300. All parameters specified in the following tables refer to these operating conditions, unless noted otherwise.

Parameter	Symbol			Values		Unit	Note /
			Min.	Тур.	Max.		Test Condition
Ambient Temperature	T <sub>A</sub>	SR	-40	-	85	°C	Temp. Range F
			-40	-	105	°C	Temp. Range X
Digital supply voltage <sup>1)</sup>	$V_{DDP}$	SR	1.8	-	5.5	V	
MCLK Frequency	$f_{\rm MCLK}$	CC	-	-	33.2	MHz	CPU clock
PCLK Frequency	$f_{PCLK}$	СС	-	-	66.4	MHz	Peripherals clock
Short circuit current of digital outputs	I <sub>SC</sub>	SR	-5	-	5	mA	
Absolute sum of short circuit currents of the device	ΣI <sub>SC_D</sub>	SR	-	_	25	mA	

Table 15 Operating Conditions Parameters

1) See also the Supply Monitoring thresholds, Chapter 3.3.2.



## 3.2 DC Parameters

## 3.2.1 Input/Output Characteristics

Table 16 provides the characteristics of the input/output pins of the XMC1300.

- Note: These parameters are not subject to production test, but verified by design and/or characterization.
- Note: Unless otherwise stated, input DC and AC characteristics, including peripheral timings, assume that the input pads operate with the standard hysteresis.

Parameter	Symbol		Limit V	/alues	Unit	Test Conditions	
			Min.	Max.			
Output low voltage on port pins	$V_{OLP}$	CC	-	1.0	V	I <sub>OL</sub> = 11 mA (5 V) I <sub>OL</sub> = 7 mA (3.3 V)	
(with standard pads)			-	0.4	V	$I_{OL} = 5 \text{ mA} (5 \text{ V})$ $I_{OL} = 3.5 \text{ mA} (3.3 \text{ V})$	
Output low voltage on high current pads	$V_{OLP1}$	СС	-	1.0	V	$I_{\rm OL}$ = 50 mA (5 V) $I_{\rm OL}$ = 25 mA (3.3 V)	
			-	0.32	V	I <sub>OL</sub> = 10 mA (5 V)	
			-	0.4	V	I <sub>OL</sub> = 5 mA (3.3 V)	
Output high voltage on port pins	V <sub>OHP</sub>	CC	V <sub>DDP</sub> - 1.0	-	V	I <sub>OH</sub> = -10 mA (5 V) I <sub>OH</sub> = -7 mA (3.3 V)	
(with standard pads)			V <sub>DDP</sub> - 0.4	-	V	I <sub>OH</sub> = -4.5 mA (5 V) I <sub>OH</sub> = -2.5 mA (3.3 V)	
Output high voltage on high current pads	$V_{OHP1}$	CC	V <sub>DDP</sub> - 0.32	-	V	I <sub>OH</sub> = -6 mA (5 V)	
			V <sub>DDP</sub> - 1.0	-	V	I <sub>OH</sub> = -8 mA (3.3 V)	
			V <sub>DDP</sub> - 0.4	-	V	I <sub>OH</sub> = -4 mA (3.3 V)	
Input low voltage on port pins (Standard Hysteresis)	$V_{ILPS}$	SR	-	$0.19 \times V_{ m DDP}$	V	CMOS Mode (5 V, 3.3 V & 2.2 V)	

 Table 16
 Input/Output Characteristics (Operating Conditions apply)





Parameter	Symbol		Limit \	/alues	Unit	Test Conditions	
			Min.	Max.			
Input Hysteresis <sup>8)</sup>	HYS	СС	$0.08 \times V_{ m DDP}$	-	V	CMOS Mode (5 V), Standard Hysteresis	
			$0.03 \times V_{ m DDP}$	-	V	CMOS Mode (3.3 V), Standard Hysteresis	
			$0.02 \times V_{ m DDP}$	-	V	CMOS Mode (2.2 V), Standard Hysteresis	
			$0.5  imes V_{ m DDP}$	$0.75  imes V_{ m DDP}$	V	CMOS Mode(5 V), Large Hysteresis	
			$0.4  imes V_{ m DDP}$	$0.75 \times V_{ m DDP}$	V	CMOS Mode(3.3 V), Large Hysteresis	
			$0.2 \times V_{ m DDP}$	$0.65 \times V_{ m DDP}$	V	CMOS Mode(2.2 V), Large Hysteresis	
Pin capacitance (digital inputs/outputs)	$C_{\rm IO}$	СС	-	10	pF		
Pull-up resistor on port pins	R <sub>PUP</sub>	СС	20	50	kohm	$V_{\rm IN} = V_{\rm SSP}$	
Pull-down resistor on port pins	R <sub>PDP</sub>	СС	20	50	kohm	$V_{\rm IN} = V_{\rm DDP}$	
Input leakage current9)	I <sub>OZP</sub>	СС	-1	1	μA	$0 < V_{\rm IN} < V_{\rm DDP},$ $T_{\rm A} \le 105 \ ^{\circ}{ m C}$	
Voltage on any pin during $V_{\rm DDP}$ power off	$V_{PO}$	SR	-	0.3	V	10)	
Maximum current per pin (excluding P1, $V_{\rm DDP}$ and $V_{\rm SS}$ )	I <sub>MP</sub>	SR	-10	11	mA	-	
Maximum current per high currrent pins	I <sub>MP1A</sub>	SR	-10	50	mA	-	
Maximum current into $V_{\text{DDP}}$ (TSSOP16, VQFN24)	$I_{\rm MVDD1}$	SR	-	130	mA	18)	
Maximum current into $V_{\text{DDP}}$ (TSSOP38, VQFN40)	I <sub>MVDD2</sub>	SR	-	260	mA	18)	

## Table 16 Input/Output Characteristics (Operating Conditions apply) (cont'd)



## Table 17 ADC Characteristics (Operating Conditions apply)<sup>1)</sup> (cont'd)

Parameter	Symbol	١	/alues	5	Unit	Note / Test Condition	
		Min.	Тур.	Max.			
Maximum sample rate in 8-bit mode <sup>3)</sup>	<i>f</i> <sub>C8</sub> CC	-	-	f <sub>ADC</sub> / 38.5	-	1 sample pending	
		-	-	f <sub>ADC</sub> / 54.5	-	2 samples pending	
RMS noise <sup>4)</sup>	EN <sub>RMS</sub> CC	-	1.5	_	LSB 12	DC input, $V_{DD} = 5.0 \text{ V},$ $V_{AIN = 2.5 \text{ V}},$ $25^{\circ}\text{C}$	
DNL error	EA <sub>DNL</sub> CC	-	±2.0	-	LSB 12		
INL error	EA <sub>INL</sub> CC	-	±4.0	-	LSB 12		
Gain error with external reference	EA <sub>GAIN</sub> CC	-	±0.5	-	%	SHSCFG.AREF = $00_B$ (calibrated)	
Gain error with internal reference 5)	EA <sub>GAIN</sub> CC	-	±3.6	-	%	SHSCFG.AREF = $1X_B$ (calibrated), -40°C - 105°C	
		-	±2.0	-	%	SHSCFG.AREF = $1X_B$ (calibrated), 0°C - 85°C	
Offset error	EA <sub>OFF</sub> CC	-	±8.0	-	mV	Calibrated, $V_{\rm DD}$ = 5.0 V	

1) The parameters are defined for ADC clock frequency  $f_{SH}$  = 32MHz, SHSCFG.DIVS = 0000<sub>B</sub>. Usage of any other frequencies may affect the ADC performance.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

4) This parameter can also be defined as an SNR value: SNR[dB] =  $20 \times \log(A_{MAXeff} / N_{RMS})$ . With  $A_{MAXeff} = 2^N / 2$ , SNR[dB] =  $20 \times \log (2048 / N_{RMS})$  [N = 12].  $N_{RMS} = 1.5$  LSB12, therefore, equals SNR =  $20 \times \log (2048 / 1.5) = 62.7$  dB.

5) Includes error from the reference voltage.



## 3.2.4 Analog Comparator Characteristics

Table 19 below shows the Analog Comparator characteristics.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 19	Analog Comparator Characteristics (Operating Conditions apply
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Parameter	Symbol		Li	mit Val	ues	Unit	Notes/
			Min.	Тур.	Max.		Test Conditions
Input Voltage	$V_{CMP}$	SR	-0.05	-	V <sub>DDP</sub> + 0.05	V	
Input Offset	$V_{CMPOFF}$	CC	-	+/-3	-	mV	High power mode $\Delta V_{\rm CMP}$ < 200 mV
			-	+/-20	-	mV	Low power mode $\Delta V_{\rm CMP}$ < 200 mV
Propagation Delay <sup>1)</sup>	t <sub>PDELAY</sub>	CC	-	25	-	ns	High power mode, $\Delta V_{\rm CMP}$ = 100 mV
			-	80	-	ns	High power mode, $\Delta V_{\rm CMP}$ = 25 mV
			-	250	_	ns	Low power mode, $\Delta V_{\rm CMP}$ = 100 mV
			-	700	-	ns	Low power mode, $\Delta V_{\rm CMP}$ = 25 mV
Current Consumption	I <sub>ACMP</sub>	CC	-	100	-	μA	First active ACMP in high power mode, $\Delta V_{\rm CMP}$ > 30 mV
			-	66	-	μA	Each additional ACMP in high power mode, $\Delta V_{CMP}$ > 30 mV
			-	10	-	μA	First active ACMP in low power mode
			_	6	-	μA	Each additional ACMP in low power mode
Input Hysteresis	$V_{\rm HYS}$	CC	-	+/-15	-	mV	
Filter Delay <sup>1)</sup>	t <sub>FDELAY</sub>	CC	-	5	-	ns	

1) Total Analog Comparator Delay is the sum of Propagation Delay and Filter Delay.



## 3.2.5 Temperature Sensor Characteristics

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Parameter	Symbol		Value	S	Unit	Note / Test Condition		
		Min.	Тур.	Max.				
Measurement time	t <sub>M</sub> CC	-	_	10	ms			
Temperature sensor range	$T_{\rm SR}{ m SR}$	-40	-	115	°C			
Sensor Accuracy <sup>1)</sup>	$T_{\text{TSAL}} \operatorname{CC}$	-6	-	6	°C	$T_{\rm J}$ > 20°C		
		-10	-	10	°C	$0^{\circ}C \le T_{J} \le 20^{\circ}C$		
		-	-/+8	-	°C	$T_{\rm J} < 0^{\circ}{\rm C}$		
Start-up time after enabling	t <sub>TSSTE</sub> SR	-	-	15	μS			

#### Table 20 Temperature Sensor Characteristics

1) The temperature sensor accuracy is independent of the supply voltage.



## 3.2.6 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Parameter	Symbol		Value	S	Unit	Note /
		Min	Typ. <sup>1)</sup>	Max.	_	Test Condition
		•				
Active mode current	$I_{\text{DDPAE}} \operatorname{CC}$	-	9.2	12	mA	32 / 64
Peripherals enabled $f = \sqrt{f}$ in MHz <sup>2</sup>		-	8.1	-	mA	24 / 48
JMCLK / JPCLK III WITZ /		_	6.6	-	mA	16 / 32
		_	5.5	-	mA	8 / 16
		_	4	-	mA	1/1
Active mode current	I <sub>DDPAD</sub> CC	_	4.8	-	mA	32 / 64
Peripherals disabled		_	4.1	-	mA	24 / 48
$f_{\rm MCLK}/f_{\rm PCLK}$ in MHz <sup>o</sup>		_	3.3	-	mA	16 / 32
		_	2.7	-	mA	8 / 16
		_	1.5	-	mA	1/1
Active mode current	I <sub>DDPAR</sub> CC	_	7.3	-	mA	32 / 64
Code execution from RAM		_	6.3	-	mA	24 / 48
$f_{MCLK} / f_{PCLK}$ in MHz		_	5.2	-	mA	16 / 32
		_	4.2	-	mA	8 / 16
		_	3.3	-	mA	1/1
Sleep mode current	I <sub>DDPSE</sub> CC	_	6.6	-	mA	32 / 64
Peripherals clock enabled			5.8	-	mA	24 / 48
JMCLK / JPCLK III IVITIZ /			5.1	-	mA	16 / 32
			4.4	-	mA	8 / 16
			3.7	-	mA	1/1

## Table 21Power Supply Parameters; VVDDP= 5V



## 3.3 AC Parameters

## 3.3.1 Testing Waveforms



## Figure 16 Rise/Fall Time Parameters



Figure 17 Testing Waveform, Output Delay



Figure 18 Testing Waveform, Output High Impedance



## 3.3.2 Power-Up and Supply Monitoring Characteristics

Table 24 provides the characteristics of the power-up and supply monitoring inXMC1300.

The guard band between the lowest valid operating voltage and the brownout reset threshold provides a margin for noise immunity and hysteresis. The electrical parameters may be violated while  $V_{\text{DDP}}$  is outside its operating range.

The brownout detection triggers a reset within the defined range. The prewarning detection can be used to trigger an early warning and issue corrective and/or fail-safe actions in case of a critical supply voltage drop.

Parameter	Symbol	V	alues		Unit	Note /
		Min.	Тур.	Max.	1	Test Condition
$V_{\rm DDP}$ ramp-up time	t <sub>RAMPUP</sub> SR	$V_{ m DDP}/$ $S_{ m VDDPrise}$	_	10 <sup>7</sup>	μs	
$V_{\text{DDP}}$ slew rate	$S_{\rm VDDPOP}~{ m SR}$	0	_	0.1	V/µs	Slope during normal operation
	S <sub>VDDP10</sub> SR	0	_	10	V/µs	Slope during fast transient within +/- 10% of V <sub>DDP</sub>
	S <sub>VDDPrise</sub> SR	0	_	10	V/µs	Slope during power-on or restart after brownout event
	$S_{\text{VDDPfall}}^{1)}$ SR	0	-	0.25	V/µs	Slope during supply falling out of the +/-10% limits <sup>2)</sup>
$V_{\text{DDP}}$ prewarning voltage	V <sub>DDPPW</sub> CC	2.1	2.25	2.4	V	ANAVDEL.VDEL_ SELECT = 00 <sub>B</sub>
		2.85	3	3.15	V	ANAVDEL.VDEL_ SELECT = 01 <sub>B</sub>
		4.2	4.4	4.6	V	ANAVDEL.VDEL_ SELECT = 10 <sub>B</sub>

# Table 24 Power-Up and Supply Monitoring Parameters (Operating Conditions apply)

Note: These parameters are not subject to production test, but verified by design and/or characterization.



## 3.3.4 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 27	SWD Interface	Timing Parameters	Operating	Conditions	apply
Table 27	SWD Interface	Timing Parameters	Operating	Conditions	app

Parameter	Symbol		Values		Unit	Note /
		Min.	Тур.	Max.		Test Condition
SWDCLK high time	t1 SR	50	-	500000	ns	-
SWDCLK low time	$t_2  \mathrm{SR}$	50	-	500000	ns	-
SWDIO input setup to SWDCLK rising edge	<i>t</i> 3 SR	10	_	_	ns	-
SWDIO input hold after SWDCLK rising edge	t <sub>4</sub> SR	10	-	-	ns	_
SWDIO output valid time	t <sub>5</sub> CC	-	-	68	ns	$C_L = 50 \text{ pF}$
after SWDCLK rising edge		-	-	62	ns	$C_L = 30 \text{ pF}$
SWDIO output hold time from SWDCLK rising edge	t <sub>6</sub> CC	4	-	-	ns	







## 3.3.5 SPD Timing Requirements

The optimum SPD decision time between  $0_B$  and  $1_B$  is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Sample	Sampling	Sample	Sample	Effective	Remark
Freq.	Factor	Clocks 0 <sub>B</sub>	Clocks 1 <sub>B</sub>	Decision	
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

#### Table 28 Optimum Number of Sample Clocks for SPD

1) Nominal sample frequency period multiplied with  $0.5 + (max. number of 0_B sample clocks)$ 

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

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#### Package and Reliability

# 4 Package and Reliability

The XMC1300 is a member of the XMC1000 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the exposed die pad may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.

## 4.1 Package Parameters

Table 35 provides the thermal characteristics of the packages used in XMC1300.

Parameter	Symbol	Lim	it Values	Unit	Package Types
		Min.	Max.		
Exposed Die Pad Dimensions	$E x \times E y$	-	2.7  imes 2.7	mm	PG-VQFN-24-19
	CC	-	3.7  imes 3.7	mm	PG-VQFN-40-13
Thermal resistance Junction-Ambient	$R_{\Theta JA}$ CC	-	104.6	K/W	PG-TSSOP-16-8 <sup>1)</sup>
		-	83.2	K/W	PG-TSSOP-28-16 <sup>1)</sup>
		-	70.3	K/W	PG-TSSOP-38-9 <sup>1)</sup>
		-	46.0	K/W	PG-VQFN-24-19 <sup>1)</sup>
		-	38.4	K/W	PG-VQFN-40-13 <sup>1)</sup>

 Table 35
 Thermal Characteristics of the Packages

1) Device mounted on a 4-layer JEDEC board (JESD 51-5); exposed pad soldered.

Note: For electrical reasons, it is required to connect the exposed pad to the board ground  $V_{SSP}$ , independent of EMC and thermal requirements.

## 4.1.1 Thermal Considerations

When operating the XMC1300 in a system, the total heat generated in the chip must be dissipated to the ambient environment to prevent overheating and the resulting thermal damage.

The maximum heat that can be dissipated depends on the package and its integration into the target board. The "Thermal resistance  $R_{\Theta JA}$ " quantifies these parameters. The power dissipation must be limited so that the average junction temperature does not exceed 115 °C.



## XMC1300 AB-Step XMC1000 Family

#### Package and Reliability



Figure 29 PG-VQFN-24-19